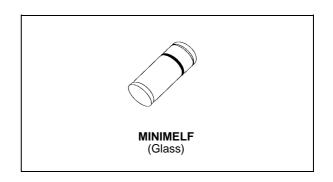
TMMBAR 10 TMMBAR 11

SMALL SIGNAL SCHOTTKY DIODES

DESCRIPTION

Metal to silicon junction diodes featuring high breakdown, low turn-on voltage and ultrafast switching.

Primarly intended for high level UHF/VHF detection and pulse application with broad dynamic range. Matched batches are available on request, (TMMBAR11 only).



ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	TMMBAR 10	TMMBAR 11	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	20	15	V
I _F	Forward Continuous Current	35	20	mA
I _{FSM}	Surge non Repetitive Forward Current	10	mA	
$T_{stg} \\ T_{j}$	Storage and Junction Temperature Range	- 65 t - 65 t	ů	
Tı	Maximum Temperature for Soldering during	26	°C	

THERMAL RESISTANCE

Symbol	Test Conditions	Value	Unit
R _{th(j-l)}	Junction-leads	400	°C/W

ELECTRICAL CHARACTERISTICS

STATIC CHARACTERISTICS

Symbol	Test Conditions			Min.	Тур.	Max.	Unit
V_{BR}	T _{amb} = 25°C	$I_R = 10\mu A$	TMMBAR 10	20			V
	T _{amb} = 25°C	$I_R = 10\mu A$	TMMBAR 11	15			
V _F *	T _{amb} = 25°C	$I_F = 1mA$				0.41	V
	T _{amb} = 25°C	$I_F = 35mA$	TMMBAR 10			1	
	T _{amb} = 25°C	$I_F = 20 \text{mA}$	TMMBAR 11			1	
I _R *	$T_{amb} = 25^{\circ}C$	$V_R = 15V$	TMMBAR 10			0.1	μΑ
	T _{amb} = 25°C	$V_R = 8V$	TMMBAR 11			0.1	

DYNAMIC CHARACTERISTICS

Symbol	Test Conditions			Min.	Тур.	Max.	Unit
С	$T_{amb} = 25^{\circ}C$	$V_R = 0V$	f = 1MHz			1.2	pF
τ	T _{amb} = 25°C	$I_F = 5mA$	Krakauer Method			100	ps

^{*} Pulse test: $t_p \le 300 \mu s \delta < 2\%$.

Matched batches available on request. Test conditions (forward voltage and/or capacitance) according to customer specification.

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Figure 1. Forward current versus forward voltage at different temperatures (typical values).

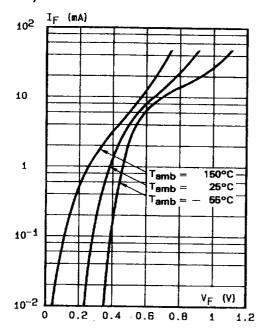


Figure 2. Forward current versus forward voltage (typical values).

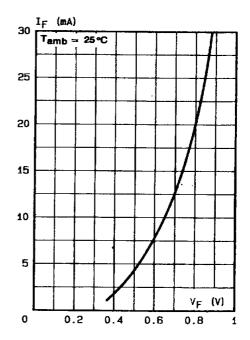


Figure 3a. Reverse current versus ambient temperature.

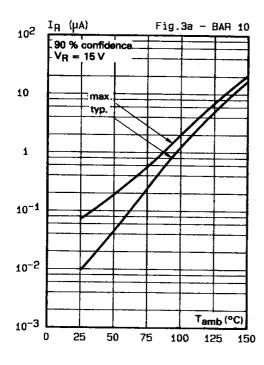


Figure 3b. Reverse current versus ambient temperature.

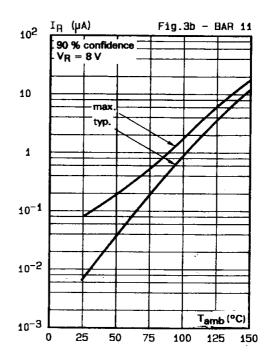


Figure 4. Reverse current versus continuous reverse voltage (typical values).

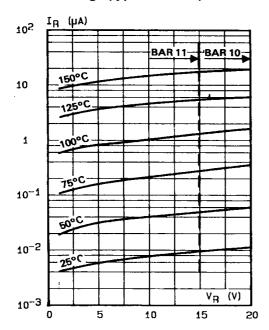
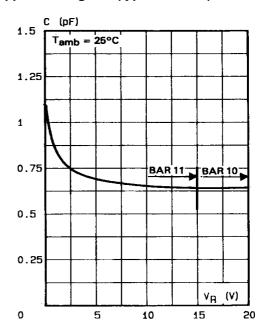


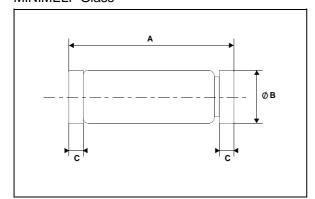
Figure 5. Capacitance C versus reverse applied voltage $V_{\mbox{\scriptsize R}}$ (typical values).

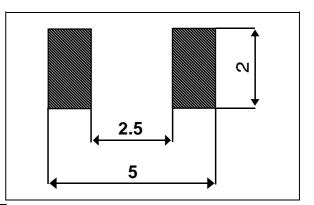


PACKAGE MECHANICAL DATA

FOOT PRINT DIMENSIONS (Millimeter)

MINIMELF Glass





	DIMENSIONS					
REF.	Millimeters		Inches			
	Min.	Max.	Min.	Max.		
Α	3.3	3.6	0.130	0.142		
В	1.59	1.62	0.063	0.064		
С	0.4	0.5	0.016	0.020		

Marking: ring at cathode end. Weight: 0.05g

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